International Rectifier

IRF1010EPbF

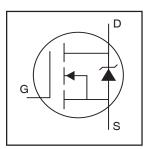
HEXFET® Power MOSFET

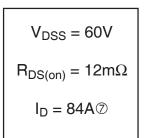
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

Description

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	84⑦	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	59	A
I _{DM}	Pulsed Drain Current ①	330	
P _D @T _C = 25°C	Power Dissipation	200	W
	Linear Derating Factor	1.4	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
I _{AR}	Avalanche Current①	50	A
E _{AR}	Repetitive Avalanche Energy①	17	mJ
dv/dt	Peak Diode Recovery dv/dt ③	4.0	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
R _{θJC}	Junction-to-Case		0.75	
R _{θCS}	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions		
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V, I_D = 250\mu A$		
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.064		V/°C	Reference to 25°C, I _D = 1mA		
R _{DS(on)}	Static Drain-to-Source On-Resistance			12	mΩ	V _{GS} = 10V, I _D = 50A ④		
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		
9fs	Forward Transconductance	69			S	V _{DS} = 25V, I _D = 50A@		
I _{DSS}	Drain-to-Source Leakage Current			25	μA	$V_{DS} = 60V, V_{GS} = 0V$		
טטי	Brain to Godice Edunage Guiterit			250	μΛ	$V_{DS} = 48V, V_{GS} = 0V, T_{J} = 150^{\circ}C$		
loss	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$		
I _{GSS}	Gate-to-Source Reverse Leakage			-100		V _{GS} = -20V		
Qg	Total Gate Charge			130		$I_D = 50A$		
Q_{gs}	Gate-to-Source Charge			28	nC	$V_{DS} = 48V$		
Q_{gd}	Gate-to-Drain ("Miller") Charge			44		V_{GS} = 10V, See Fig. 6 and 13		
t _{d(on)}	Turn-On Delay Time		12			$V_{DD} = 30V$		
t _r	Rise Time		78		ns	$I_D = 50A$		
t _{d(off)}	Turn-Off Delay Time		48		115	$R_G = 3.6\Omega$		
t _f	Fall Time		53			V _{GS} = 10V, See Fig. 10 ⊕		
L _D	Internal Drain Inductance		4.5			Between lead,		
ъ	Internal Brain Inductance		4.5		nH	6mm (0.25in.)		
_	Internal Source Inductance		7.5		11111	from package		
L _S	Internal Source Inductance		7.5			and center of die contact		
C _{iss}	Input Capacitance		3210			V _{GS} = 0V		
C _{oss}	Output Capacitance		690			$V_{DS} = 25V$		
C _{rss}	Reverse Transfer Capacitance		140		pF	f = 1.0MHz, See Fig. 5		
E _{AS}	Single Pulse Avalanche Energy ²		1180ଔ	320⑥	mJ	I _{AS} = 50A, L = 260μH		

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			84⑦		MOSFET symbol
	(Body Diode)		8		A	showing the
I _{SM}	Pulsed Source Current			330		integral reverse
	(Body Diode)①			330		p-n junction diode.
V _{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 50A$, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		73	110	ns	$T_J = 25^{\circ}C, I_F = 50A$
Q _{rr}	Reverse Recovery Charge		220	330	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\label{eq:target} \begin{tabular}{ll} \hline @ Starting $T_J=25^\circ$C, $L=260\mu$H \\ $R_G=25\Omega$, $I_{AS}=50A$, $V_{GS}=10V$ (See Figure 12) \\ \hline \end{tabular}$
- $\label{eq:loss} \begin{array}{l} \mbox{\Large \ \ \, } I_{SD} \leq 50A, \mbox{ di/dt} \leq 230A/\mu s, \mbox{ } V_{DD} \leq V_{(BR)DSS}, \\ \mbox{\scriptsize \ \, } T_J \leq 175^{\circ}\mbox{\scriptsize \ \, C} \end{array}$
- 4 Pulse width \leq 400 μ s; duty cycle \leq 2%.
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- © This is a calculated value limited to $T_J = 175$ °C.
- Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.

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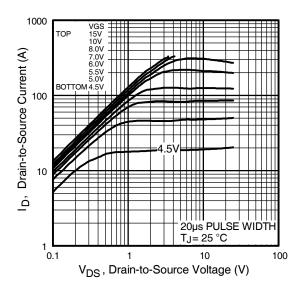


Fig 1. Typical Output Characteristics

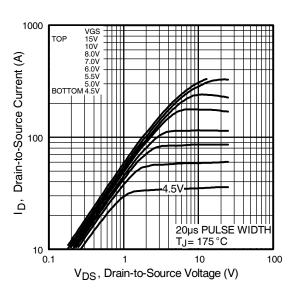


Fig 2. Typical Output Characteristics

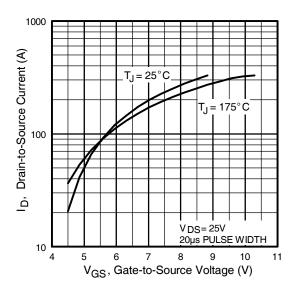


Fig 3. Typical Transfer Characteristics

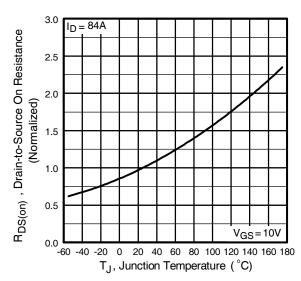


Fig 4. Normalized On-Resistance Vs. Temperature

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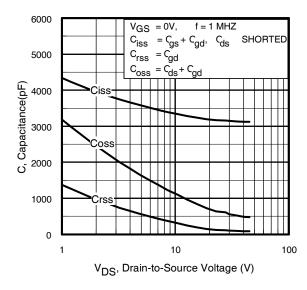


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

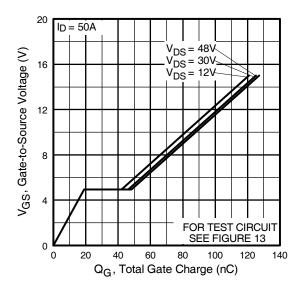


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

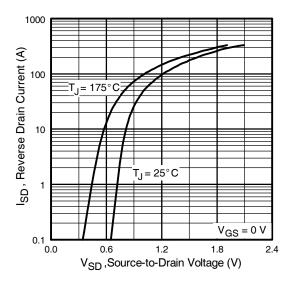


Fig 7. Typical Source-Drain Diode Forward Voltage

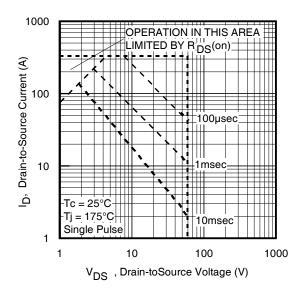


Fig 8. Maximum Safe Operating Area

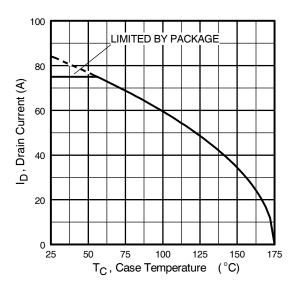


Fig 9. Maximum Drain Current Vs. Case Temperature

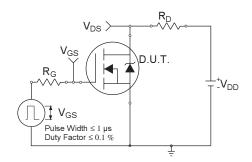


Fig 10a. Switching Time Test Circuit

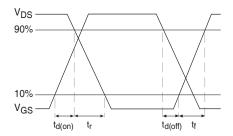


Fig 10b. Switching Time Waveforms

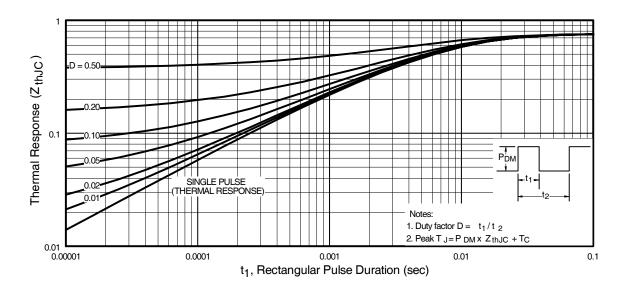


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

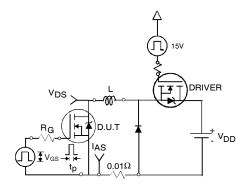


Fig 12a. Unclamped Inductive Test Circuit

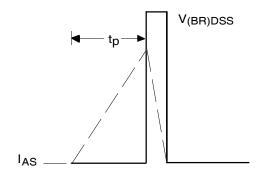


Fig 12b. Unclamped Inductive Waveforms

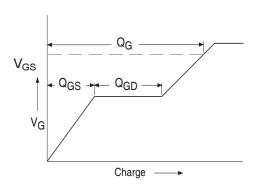


Fig 13a. Basic Gate Charge Waveform

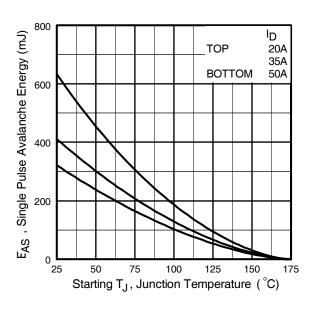


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

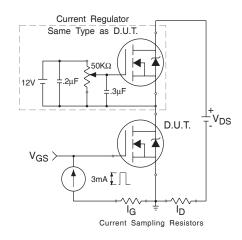
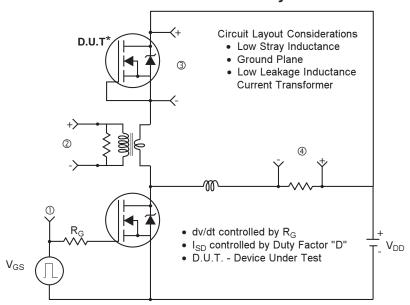


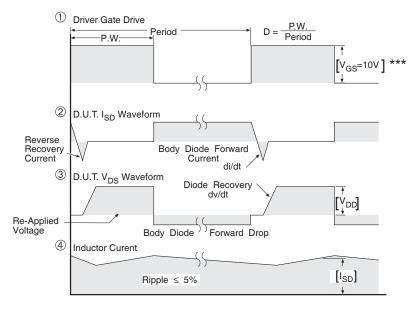
Fig 13b. Gate Charge Test Circuit

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Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel

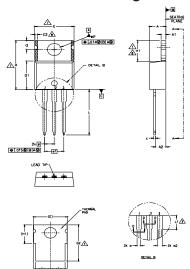


*** V_{GS} = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

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TO-220AB Package Outline (Dimensions are shown in millimeters (inches))



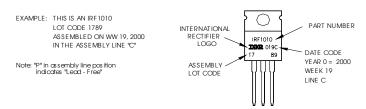
1	DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.
2	DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
3	LEAD DIMENSION AND FINISH UNCONTROLLED IN L1,
4	DIMENSION D, D1 & E DD NOT INCLUDE MOLD FLASH. MOLD FLASH
	SHALL NOT EXCEED .005" (0.127) PER SIDE, THESE DIMENSIONS ARE
^	MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY,
5.	DIMENSION b1, b3 & c1 APPLY TO BASE METAL ONLY.
6	CONTROLLING DIMENSION: INCHES,
7	THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
8	DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING
	AND SINGULATION IRREGULARITIES ARE ALLOWED.

OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIM	ETERS	INC		
	MIN.	MAX.	MIN.	MAX.	NOTES
Α	3.56	4.83	.140	.190	
A1	0.51	1.40	.020	,055	
A2	2.03	2.92	.080	.115	
b	0.38	1,01	.015	.040	
ь1	0.38	0.97	.015	.038	5
b2	1,14	1.78	.045	.070	
b3	1,14	1,73	.045	.068	5
С	0.36	0.61	.014	.024	
c1	0.36	0,56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11,68	12.88	.460	.507	7
E	9.65	10,67	.380	.420	4,7
E1	6,86	8.89	.270	.350	7
E2	-	0.76	-	.030	8
e	2.54	BSC	.100	BSC	
e1	5.08	BSC	.200	BSC	
Hf	5.84	6.86	.230	.270	7,8
L	12.70	14,73	.500	.580	
L1	-	6.35	-	.250	3
øΡ	3,54	4,08	,139	,161	
Q	2.54	3.42	.100	.135	

LEAD ASSIGNMENTS
HEXFET
1 GATE 2 DRAIN 3 SOURCE
IGBTs, CoPACK
1,- GATE 2,- COLLECTOR 3,- EMITTER
DIGDES
1,- ANODE/OPEN 2 CATHODE 3 ANODE

TO-220AB Part Marking Information



Notes:

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- 1. For an Automotive Qualified version of this part please see http://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.



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